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SUBSTITUTE SPECIFICATION CLEAN VERSION

METHOD AND APPARATUS FOR RECOGNIZING A STRUCTURE TO BE APPLIED ONTO A SUBSTRATE WITH MULTIPLE CAMERAS

ABSTRACT OF THE DISCLOSURE

A method and apparatus are provided for automatic application and monitoring of a structure to be applied onto substrate. A plurality of cameras positioned around an application facility are utilized to monitor the automatic application of a structure on a substrate by means of a stereometry procedure. Three-dimensional recognition of a reference contour position results in the overlapping area to be used for gross adjustment of the application facility prior to applying the structure.